- Designed for Signaling Rates $\dagger$ up to 150 Mbps
- Low-Voltage Differential Signaling With Typical Output Voltage of 700 mV and a 100- $\Omega$ Load
- Propagation Delay Time of 2.3 ns, Typical
- Single 3.3-V Supply Operation
- One Driver's Power Dissipation at 75 MHz , 50 mW , Typical
- High Impedance Outputs When Disabled or With $\mathrm{V}_{\mathrm{CC}}<1.5 \mathrm{~V}$
- Bus-Pin ESD Protection Exceeds 12 kV
- Low-Voltage CMOS (LVCMOS) Logic Input Levels Are 5-V Tolerant


## description

The SN65LVDM31 incorporates four differential line drivers that implement the electrical characteristics of low-voltage differential signaling. This product offers a low-power alternative to $5-\mathrm{V}$ PECL drivers with similar signal levels. Any of the four current-mode drivers will deliver a minimum differential output voltage magnitude of 540 mV into a $100-\Omega$ load when enabled by either an active-low or active-high enable input.
The intended application of this device and signaling technique is for both point-to-point and multiplexed baseband data transmission over controlled impedance media of approximately $100 \Omega$. The transmission media may be printed-circuit board traces, backplanes, or cables. The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media and the noise coupling to the environment.

The SN65LVDM31 is characterized for operation from $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$.
FUNCTION TABLE

| INPUT | ENABLES |  | OUTPUTS |  |
| :---: | :---: | :---: | :---: | :---: |
| A | G | $\bar{G}$ | Y | Z |
| H | $H$ | X | $H$ | L |
| L | $H$ | X | L | $H$ |
| H | X | L | $H$ | L |
| L | X | L | L | $H$ |
| X | L | H | Z | Z |
| Open | $H$ | X | L | $H$ |
| Open | X | L | L | $H$ |

## equivalent input and output schematic diagrams


absolute maximum ratings over operating free-air temperature (unless otherwise noted) $\dagger$


VOY or VOZ ................................................................... -0.5 V to 4 V
Electrostatic discharge, (see Note 2): Y, Z, and GND .......................... Class 3, A:12 kV, B:600 V All pins ................................... Class $3, A: 7 \mathrm{kV}, \mathrm{B}: 500 \mathrm{~V}$
Continuous power dissipation ............................................... See Dissipation Rating Table
Storage temperature range .................................................................. $-65^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$
Lead temperature $1,6 \mathrm{~mm}$ ( $1 / 16 \mathrm{inch}$ ) from case for 10 seconds .................................. $260^{\circ} \mathrm{C}$
$\dagger$ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTES: 1. All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.
2. Tested in accordance with MIL-STD-883C Method 3015.7.

DISSIPATION RATING TABLE

| PACKAGE | $\mathbf{T}_{\mathbf{A}} \leq 25^{\circ} \mathbf{C}$ <br> POWER RATING | OPERATING FACTOR $\ddagger$ <br> ABOVE TA $=25^{\circ} \mathbf{C}$ | $\mathbf{T}_{\mathbf{A}}=85^{\circ} \mathbf{C}$ <br> POWER RATING |
| :---: | :---: | :---: | :---: |
| D | 950 mW | $7.6 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ | 494 mW |

$\ddagger$ This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.
recommended operating conditions

|  | MIN | NOM | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: |
| Supply voltage, $\mathrm{V}_{\mathrm{CC}}$ | 3 | 3.3 | 3.6 | V |
| High-level input voltage, $\mathrm{V}_{\mathrm{IH}}$ | 2.5 |  |  | V |
| Low-level input voltage, $\mathrm{V}_{\text {IL }}$ |  |  | 0.9 | V |
| Operating free-air temperature, $\mathrm{T}_{\mathrm{A}}$ | -40 |  | 85 | ${ }^{\circ} \mathrm{C}$ |

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electrical characteristics over recommended operating conditions (unless otherwise noted)

|  | PARAMETER | TEST CONDITIONS |  | MIN | TYP† | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| \|VOD| | Differential output voltage magnitude | $\mathrm{R}_{\mathrm{L}}=100 \Omega$, | See Figure 2 | 540 | 700 | 860 | mV |
|  |  | $\mathrm{R}_{\mathrm{L}}=50 \Omega$, | See Figure 2 | 270 | 350 | 430 |  |
| $\Delta \mathrm{V}_{\text {OD }}$ | Change in differential output voltage magnitude between logic states | See Figure 2 |  | -25 | 0 | 25 | mV |
| VOC(SS) | Steady-state common-mode output voltage | See Figure 3 |  | 1.14 | 1.2 | 1.3 | V |
| $\triangle \mathrm{V}$ OC(SS) | Change in steady-state common-mode output voltage between logic states |  |  | -30 | 0 | 30 | mV |
| VOC(PP) | Peak-to-peak common-mode output voltage |  |  |  | 70 | 100 |  |
| ICC | Supply current | Enabled, No load | $\mathrm{V}_{\mathrm{IN}}=0$ or $\mathrm{V}_{\mathrm{CC}}$ |  | 6 | 10 | mA |
|  |  | Enabled, $\mathrm{R}_{\mathrm{L}}=100 \Omega$ |  |  | 35 | 40 |  |
|  |  | Disabled |  |  | 0.5 | 0.7 |  |
| $\mathrm{IIH}^{\text {H }}$ | High-level input current | $\mathrm{V}_{\mathrm{IH}}=3 \mathrm{~V}$ |  | -10 | 3 | 10 | $\mu \mathrm{A}$ |
| IIL | Low-level input current | $\mathrm{V}_{\mathrm{IL}}=0 \mathrm{~V}$ |  | -10 | 0 | 10 | $\mu \mathrm{A}$ |
| Ios | Short-circuit output current | $\mathrm{V}_{\mathrm{OY}}$ or $\mathrm{V}_{\mathrm{OZ}}=0 \mathrm{~V}$ |  |  | 7 | 10 | mA |
|  |  | $\mathrm{V}_{\mathrm{OD}}=0 \mathrm{~V}$ |  |  | 7 | 10 |  |
| loz | High-impedance state output current | $\mathrm{V}_{\mathrm{O}}=0 \mathrm{~V}$ or $\mathrm{V}_{\mathrm{CC}}$ |  |  |  | $\pm 1$ | $\mu \mathrm{A}$ |
| IO(OFF) | Power-off output current | $\mathrm{V}_{\mathrm{CC}}=1.5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{O}}=3.6 \mathrm{~V}$ |  |  | $\pm 1$ | $\mu \mathrm{A}$ |

$\dagger$ All typical values are at $25^{\circ} \mathrm{C}$ and with a 3.3 V supply.

## switching characteristics over recommended operating conditions (unless otherwise noted)

|  | PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| tplH | Propagation delay time, low-to-high-level output | See Figure 4 | 1.8 | 2.3 | 2.9 | ns |
| tPHL | Propagation delay time, high-to-low-level output |  | 1.8 | 2.3 | 2.9 | ns |
| $\mathrm{tr}_{r}$ | Differential output signal rise time |  | 0.4 | 0.6 | 1.0 | ns |
| $\mathrm{t}_{\mathrm{f}}$ | Differential output signal fall time |  | 0.4 | 0.6 | 1.0 | ns |
| $\left.\mathrm{t}_{\text {sk( }} \mathrm{p}\right)$ | Pulse skew (\|tpHL - tpLH|) |  |  | 50 | 350 | ns |
| tsk(0) | Channel-to-channel output skew (see Note 3) |  |  |  | 200 | ns |
| $\mathrm{t}_{\text {sk }}(\mathrm{pp})$ | Part-to-part skew (see Note 4) | See Figure 5 |  |  | 1 | ns |
| tpZH | Propagation delay time, high-impedance-to-high-level output |  |  | 6 | 15 | ns |
| tPZL | Propagation delay time, high-impedance-to-low level output |  |  | 6 | 15 | ns |
| tPHz | Propagation delay time, high-level-to-high-impedance output |  |  | 6 | 15 | ns |
| tPLZ | Propagation delay time, low-level-to-high-impedance output |  |  | 6 | 15 | ns |

NOTES: 3. $\mathrm{t}_{\mathrm{sk}}(0)$ is the maximum delay time difference between drivers on the same device.
4. $\mathrm{t}_{\mathrm{sk}(\mathrm{pp})}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

## PARAMETER MEASUREMENT INFORMATION



Figure 1. Driver Voltage and Current Definitions


Figure 2. VOD Test Circuit


NOTE: All input pulses are supplied by a generator having the following characteristics: $t_{r}$ or $t_{f} \leq 1 \mathrm{~ns}$, pulse repetition rate (PRR) $=0.5 \mathrm{Mpps}$, pulsewidth $=500 \pm 10 \mathrm{~ns}$. $C_{L}$ includes instrumentation and fixture capacitance within $0,06 \mathrm{~mm}$ of the DUT. The measurement of $V_{O C}(P P)$ is made on test equipment with $\mathrm{a}-3 \mathrm{~dB}$ bandwidth of at least 300 MHz .

Figure 3. Test Circuit and Definitions for the Driver Common-Mode Output Voltage

## PARAMETER MEASUREMENT INFORMATION

Input


NOTE: All input pulses are supplied by a generator having the following characteristics: $\mathrm{t}_{\mathrm{r}}$ or $\mathrm{t}_{\mathrm{f}} \leq 1 \mathrm{~ns}$, pulse repetition rate (PRR) $=50 \mathrm{Mpps}$, pulsewidth $=10 \pm 0.2 \mathrm{~ns}$. CL includes instrumentation and fixture capacitance within $0,06 \mathrm{~mm}$ of the DUT.

Figure 4. Test Circuit, Timing, and Voltage Definitions for the Differential Output Signal


NOTE: All input pulses are supplied by a generator having the following characteristics: $\mathrm{t}_{\mathrm{r}}$ or $\mathrm{t}_{\mathrm{f}} \leq 1 \mathrm{~ns}$, pulse repetition rate (PRR) $=0.5 \mathrm{Mpps}$, pulsewidth $=500 \pm 10 \mathrm{~ns}$. $C_{L}$ includes instrumentation and fixture capacitance within $0,06 \mathrm{~mm}$ of the DUT.

Figure 5. Enable and Disable Time Circuit and Definitions

## MECHANICAL DATA

D (R-PDSO-G**)
PLASTIC SMALL-OUTLINE PACKAGE
14 PINS SHOWN


NOTES: A. All linear dimensions are in inches (millimeters).
B. This drawing is subject to change without notice.
C. Body dimensions do not include mold flash or protrusion, not to exceed $0.006(0,15)$.
D. Falls within JEDEC MS-012

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